







ISO/IEC17025 Accredited Lab.

Report No: FCC 0808060 File reference No: 2008-11-15

Applicant: WIN ACCORD LTD.

Product: DF-P8X

Brand Name: N/A

Model No: Digital Photo Frame

Test Standards: FCC Part 15 Subpart B: 2006

Test result:

It is herewith confirmed and found to comply with the requirements

set up by ANSI C63.4&FCC Part 15 regulations for the evaluation of

electromagnetic compatibility

Approved By

Jack Chung

Jack Chung

Manager

Dated: Nov 15. 2008

Results appearing herein relate only to the sample tested

The technical reports is issued errors and omissions exempt and is subject to withdrawal at

SHENZHEN TIMEWAY TECHNOLOGY CONSULTING CO LTD

East 5/Block 4, Anhua Industrial Zone, No.8, Tairan Rd. Chegongmiao, FuTian District, Shenzhen, CHINA.

Tel (755) 83448688 Fax (755) 83442996

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Special Statement:

The testing quality ability of our laboratory meet with "Quality Law of People's Republic of China" Clause 19.

The testing quality system of our laboratory meet with ISO/IEC-17025 requirements, which is approved by CNAS. This approval result is accepted by MRA of APLAC.

Our test facility is recognized, certified, or accredited by the following organizations:

CNAS-LAB Code: L2292

The EMC Laboratory has been assessed and in compliance with CNAS-CL01 accreditation criteria for testing Laboratories (identical to ISO/IEC 17025:2005 General Requirements) for the Competence of testing Laboratories.

FCC-Registration No.: 899988

The EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications commission. The acceptance letter from the FCC is maintained in our files. Registration No.: 899988.

IC-Registration No.: IC5205A-01

The EMC Laboratory has been registered and fully described in a report filed with the (IC) Industry Canada. The acceptance letter from the IC is maintained in our files. Registration IC No.: 5205A-01.

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1.0 General Details

1.1 Test Lab Details

Name: SHENZHEN TIMEWAY TECHNOLOGY CONSULTING CO LTD

Address: East 5/Block 4, Anhua Industrial Zone, No.8, Tairan Rd. CheGongMiao, FuTian District,

Shenzhen, CHINA.

Telephone: (755) 83448688 Fax: (755) 83442996

1.2 Applicant Details

Applicant: WIN ACCORD LTD.

Address: 12F,NO.225,SEC 5,105 SONG SHAN DIST.,NAN JING EAST

ROAD, TAIPEI, TAIWAN, R.O.C

Telephone: 02-2749 3837 Fax: 02-2749-3918

1.3 Description of EUT

Product: Digital Photo Frame
Manufacturer: WIN ACCORD LTD.

Address: Shatou Section. Zhen'an Road, Chang'an, Town, Dongguan City

Brand Name: N/A Model Number: DF-P8X

Additional Model XSJ-008431B, XSJ-008431X (X:A-Z,0-9,a-z)

Number:

Rating: Input: DC 12V, 2A

1.4 Submitted Sample: 1 Sample

The sample tested by

1.5 Test Duration

2008-09-26 to 2008-11-14

1.6 Test Uncertainty

Conducted Emissions Uncertainty =3.6dB Radiated Emissions Uncertainty =4.7dB

1.7 Test Engineer

land land

Print Name: Terry Tang

The report refers only to the sample tested and does not apply to the bulk.

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2.0 List of Measurement Equipment

2.1 Conducted Emission Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EMI Test Receiver	ESCS30	830245/009	RS	2008.2.23	1Year
Coaxial Switch	MP59B	M70585	ANRITSU	N/A	N/A
LISN	NTFM8132	8132137	SCHWARZBECK	2008.2.24	1Year
LISN	NTFM8134	8134109	SCHWARZBECK	2008.2.24	1Year
LISN	NTFM8136	8136102	SCHWARZBECK	2008.2.24	1Year

2.2 Radiated electromagnetic disturbance test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EMI Test Receiver	ESCS30	830245/009	RS	2008.2.23	1Year
Coaxial Switch	MP59B	M70585	ANRITSU	N/A	N/A
Spectrum Analyzer(with					
Tracking Generator)	MS2661C	MT72089	ANRITSU	2008.2.23	1Year
Amplifier	MH648A	M20494	ANRITSU	2008.2.24	1Year
Bilog Antenna	CBL6101C	2576	CHASE	2008.2.23	1Year

2.3 Auxiliary Equipment

					Calibration
Name	Model No.	Serial No.	Manufacturer	Calibration Date	Cycle
Electronic					
Equipment	MT-20	WNDGDZC-080	Derfu	N/A	N/A
Adaptor	SB3D-040-1MWND	9960641	SUNSHEN	N/A	N/A

2.4 I/O Cable

Cable No.	Cable No. Port		Cable Type	Cable Length
1	Communication port	N/A	Data communication	1.0

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3.0 **Technical Details**

3.1 **Investigations Requested** Perform Electromagnetic Interference [EMI] tests for FCC Requirement.

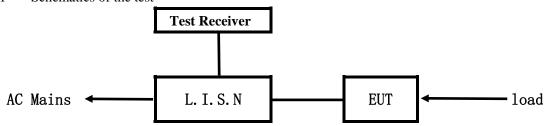
3.2 Test Standards

FCC Part 15 Subpart B: 2006



4.0 Conducted Power line Test

4.1 Schematics of the test

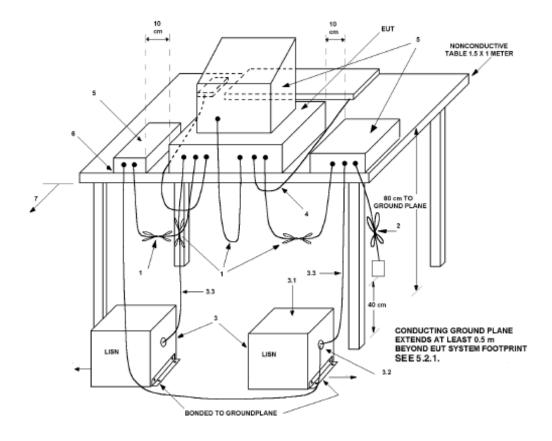


EUT: Equipment Under Test

4.2 Test Method and test Procedure

The EUT was tested according to ANSI C63.4-2003. The Frequency spectrum From 0.15MHz to 30MHz was investigated. The LISN used was 50ohm/50uH as specified by section 5.1 of ANSI C63.4 –2003. Cables and peripherals were moved to find the maximum emission levels for each frequency.

Block diagram of Test setup



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4.3 Power line conducted Emission Limit

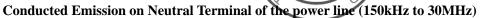
Eroguanay (MHz)	Class A Li	mits dB(μV)	Class B Limits dB(μV)		
Frequency(MHz)	Quasi-peak Level	Average Level	Quasi-peak Level	Average Level	
$0.15 \sim 0.50$	79.00	66.00	66.00~56.00*	56.00~46.00*	
$0.50 \sim 5.00$	73.00	60.00	56.00	46.00	
5.00 ~ 30.00	73.00	60.00	60.00	50.00	

Notes: 1. *decreasing linearly with logarithm of frequency.

2. The tighter limit shall apply at the transition frequencies

4.4 Test Results

The frequency spectrum from 0.15MHz to 30MHz was investigated. All reading are quasi-peak values with a resolution bandwidth of 9kHz.

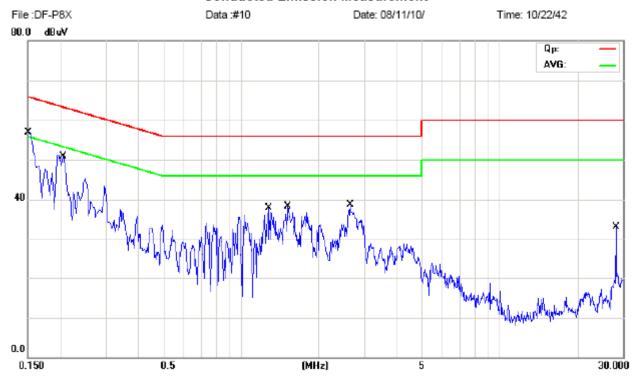


EUT set Condition: Playing SD Card Working Voltage: 120V~ 60Hz

Results: Pass

Please refer to following diagram for individual

Conducted Emission Measurement



Г		Reading	Limit			
Frequency (MHz)	Live		Neutral		(dB µ V)	
(MHZ)	Quasi-peak	Average	Quasi-peak	Average	Quasi-peak	Average
0.1508			53.50	38.00	65.96	55.96
0.2056			43.46	38.26	63.38	53.38
1.2796			33.31	23.11	56.00	46.00
1.5227			31.51	21.61	56.00	46.00
2.6617			32.16	22.96	56.00	46.00
28.2043			26.24	13.94	60.00	50.00

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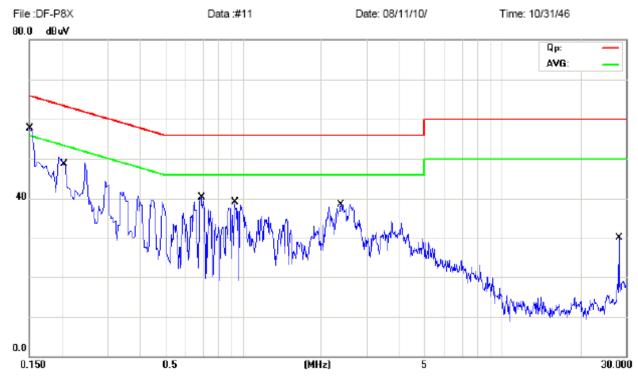


Conducted Emission on Live Terminal of the power line (150kHz to 30MHz)

EUT set Condition: Playing SD Card Working Voltage: 120V~ 60Hz

Results: Pass
Please refer to following diagram for individual

Conducted Emission Measurement



Eng gran av		Reading	Limit			
Frequency (MHz)	Live		Neutral		(dB µ V)	
(WITIZ)	Quasi-peak	Average	Quasi-peak	Average	Quasi-peak	Average
0.1508	54.50	40.10			65.96	55.96
0.2057	45.86	32.36			63.38	53.38
0.6892	34.97	25.37			56.00	46.00
0.9300	34.23	20.83			56.00	46.00
2.3852	33.15	24.15			56.00	46.00
28.2071	26.54	13.94			60.00	50.00

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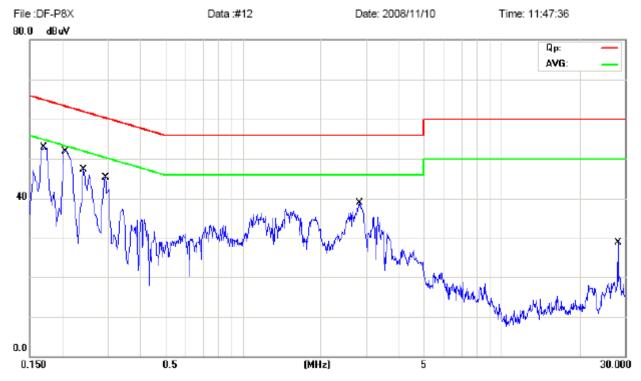
Conducted Emission on Neutral Terminal of the power line (150kHz to 30MHz)

EUT set Condition: Playing CF Card Working Voltage: 120V~ 60Hz

Results: Pass

Please refer to following diagram for individual

Conducted Emission Measurement



Engguenav		Reading	Limit			
Frequency (MHz)	Live		Neutral		$(dB \mu V)$	
(MHZ)	Quasi-peak	Average	Quasi-peak	Average	Quasi-peak	Average
0.1705			49.82	24.62	64.94	54.94
0.2064			46.76	25.86	63.35	53.35
0.2418			43.00	17.60	62.03	52.03
0.2983			41.25	20.05	60.42	50.42
2.8230			33.63	17.63	56.00	46.00
28.2297			27.94	17.64	60.00	50.00

The report refers only to the sample tested and does not apply to the bulk.



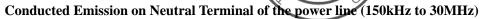
Conducted Emission on Live Terminal of the power line (150kHz to 30MHz)

EUT set Condition: Playing CF Card Working Voltage: 120V~ 60Hz

Results: Pass
Please refer to following diagram for individual

Conducted Emission Measurement

Engguenav		Reading	Limit			
Frequency (MHz)	Live		Live Neutral		$(dB \mu V)$	
(MHZ)	Quasi-peak	Average	Quasi-peak	Average	Quasi-peak	Average
0.1655	51.12	39.12			65.18	55.18
0.2054	47.16	33.46			63.39	53.39
0.2940	44.15	28.05			60.41	50.41
2.4155	34.77	17.37			56.00	46.00

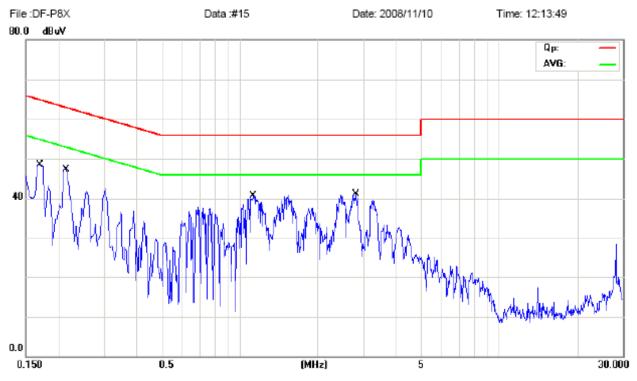


EUT set Condition: Playing USB Working Voltage: 120V~60Hz

Results: Pass

Please refer to following diagram for individual

Conducted Emission Measurement



Enganan ar		Reading	Limit			
Frequency (MHz)	Live		Neutral		$(dB \mu V)$	
(WITIZ)	Quasi-peak	Average	Quasi-peak	Average	Quasi-peak	Average
0.1688	-	1	48.32	35.12	65.02	55.02
0.2122	-	1	44.57	30.27	63.12	53.12
1.1343			36.15	19.75	56.00	46.00
2.8173			35.83	23.43	56.00	46.00

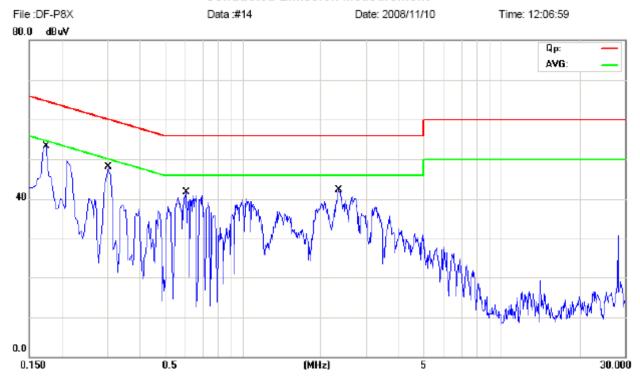


Conducted Emission on Live Terminal of the power line (150kHz to 30MHz)

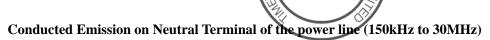
EUT set Condition: Playing USB Working Voltage: 120V~ 60Hz

Results: Pass
Please refer to following diagram for individual

Conducted Emission Measurement



F		Reading	Limit			
Frequency (MHz)	Live	Live		Neutral		V)
(WITIZ)	Quasi-peak	Average	Quasi-peak	Average	Quasi-peak	Average
0.1704	49.43	39.73			64.77	54.77
0.3020	44.76	40.06			60.19	50.19
0.6064	36.98	22.54			56.00	46.00
2.3504	37.24	26.03			56.00	46.00



EUT set Condition: Connected to PC Working Voltage: 120V~ 60Hz

Results: Pass

Please refer to following diagram for individual

Conducted Emission Measurement



Eno avon ov	Reading(dB µ V)			Limit		
Frequency (MHz)	Live	;	Neutral		(dB µ V)	
(WITIZ)	Quasi-peak	Average	Quasi-peak	Average	Quasi-peak	Average
0.1655			48.52	36.82	65.18	65.18
0.2098			44.16	29.76	63.21	63.21
2.5580			36.42	21.22	56.00	56.00

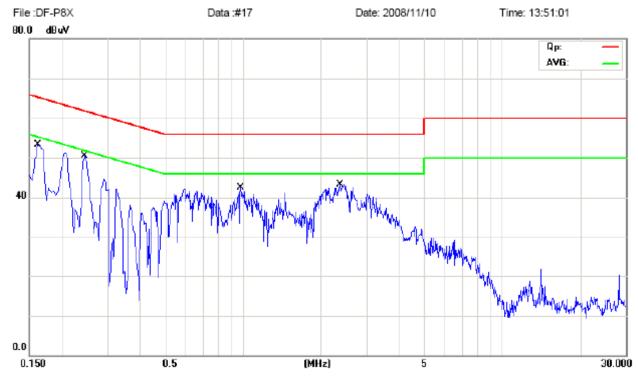


Conducted Emission on Live Terminal of the power line (150kHz to 30MHz)

EUT set Condition: Connected to PC Working Voltage: 120V~ 60Hz

Results: Pass
Please refer to following diagram for individual

Conducted Emission Measurement



Eraguanav	Reading(dB µ V)				Limit	
Frequency (MHz)	Live	ve Neutral		$(dB \mu V)$		
(WITIZ)	Quasi-peak	Average	Quasi-peak	Average	Quasi-peak	Average
0.1621	50.31	37.71			65.36	55.36
0.2454	46.10	35.50			61.91	51.91
0.9842	35.58	17.88			56.00	46.00
2.3826	37.25	20.35			56.00	46.00

The report refers only to the sample tested and does not apply to the bulk.

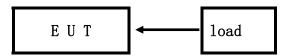
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5.0 Radiated Disturbance Test

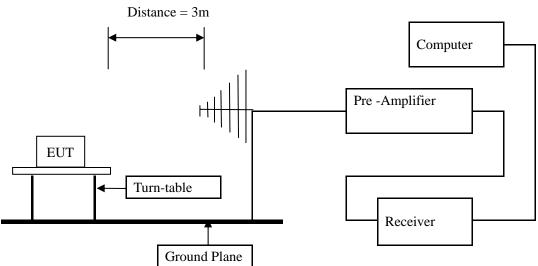
5.1 Schematics of the test



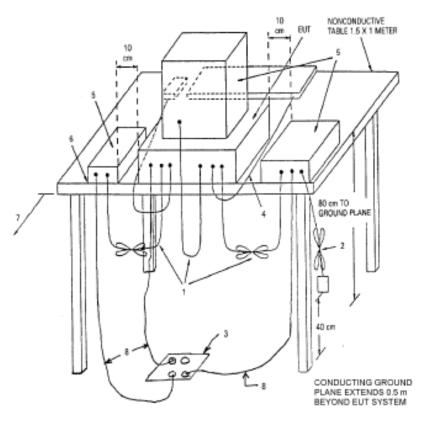
5.2 Test Method and test Procedure:

The EUT was tested according to ANSI C63.4 –2003, The frequency spectrum from 30MHz to 1GHz was investigated. All reading from 30MHz to 1GHz are quasi-peak 0values with a resolution bandwidth of 120KHz. All readings are above 1GHz, peak values with a resolution bandwidth of 1MHz. Measurements were made at 3 meters.

Block diagram of Test setup







5.3 Radiated Emission Limit

Frequency Range (MHz)	Distance (m)	Field strength (dB µ V/m)
30-88	3	40.00
88-216	3	43.50
216-960	3	46.00
Above 960	3	54.00

Note: The lower limit shall apply at the transition frequencies

5.4 Test result

The frequency spectrum from 30MHz to 1GHz was investigated. All reading from 30MHz to 1GHz are quasi-peak values with a resolution bandwidth of 120KHz. All readings are above 1GHz, peak values with a resolution bandwidth of 1MHz. Measurements were made at 3 meters.

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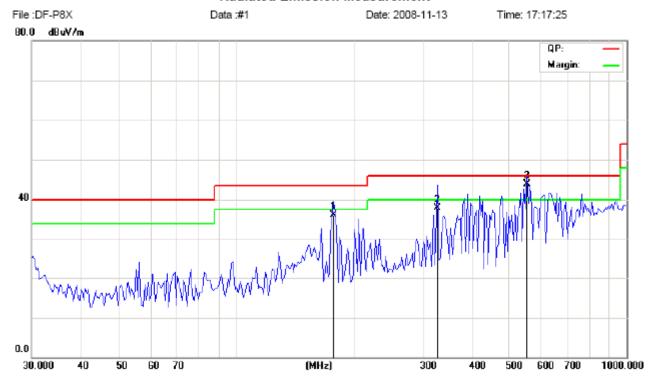
A: Radiated Disturbance In Horizontal (30MHz----1000MHz)

EUT set Condition: Connected to PC

Level: Class B
Results: PASS

Please refer to following diagram for individual

Picture of the test



Frequency (MHz)	Level@3m (dBµV/m)	Antenna Polarity	Limit@3m (dBµV/m)
177.259	36.01	Н	43.50
327.571	37.92	Н	46.00
555.083	43.96	Н	46.00

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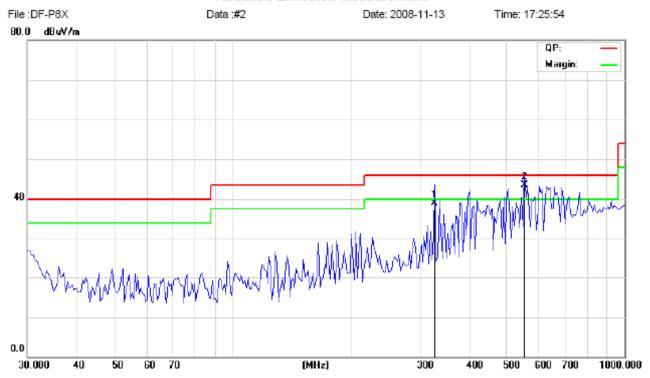
B: Radiated Disturbance In Vertical (30MHz---1000MHz)

EUT set Condition: Connected to PC

Level: Class B
Results: PASS

Please refer to following diagram for individual

Picture of the test



Frequency (MHz)	Level@3m ($dB\mu V/m$)	Antenna Polarity	Limit@3m ($dB\mu V/m$)
327.340	38.93	V	46.00
554.512	43.48	V	46.00

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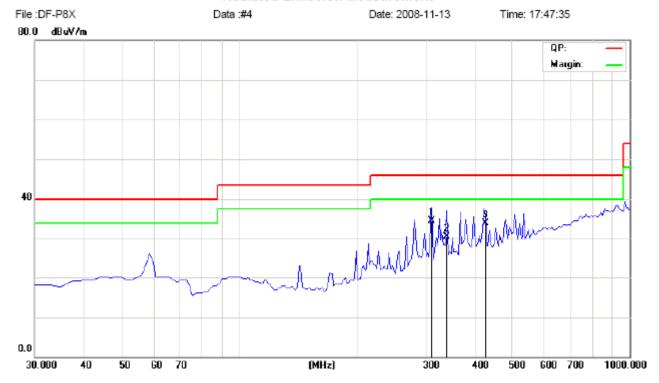


EUT set Condition: Reading CF Card

Level: Class B
Results: PASS

Please refer to following diagram for individual

Picture of the test



Frequency (MHz)	Level@3m (dBµV/m)	Antenna Polarity	Limit@3m (dBµV/m)
310.578	34.53	Н	46.00
338.616	30.42	Н	46.00
423.604	33.87	Н	46.00

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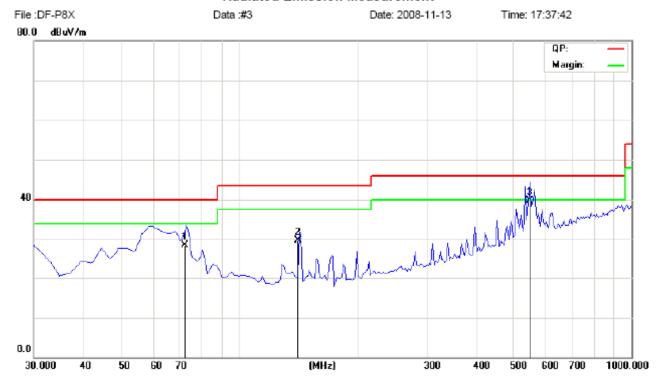
D: Radiated Disturbance In Vertical (30MHz---1000MHz)

EUT set Condition: Reading CF Card

Level: Class B
Results: PASS

Please refer to following diagram for individual

Picture of the test



Frequency (MHz)	Level@3m (dBµV/m)	Antenna Polarity	Limit@3m (dBµV/m)
72.571	28.45	V	40.00
141.100	29.73	V	43.50
550.561	39.80	V	46.00

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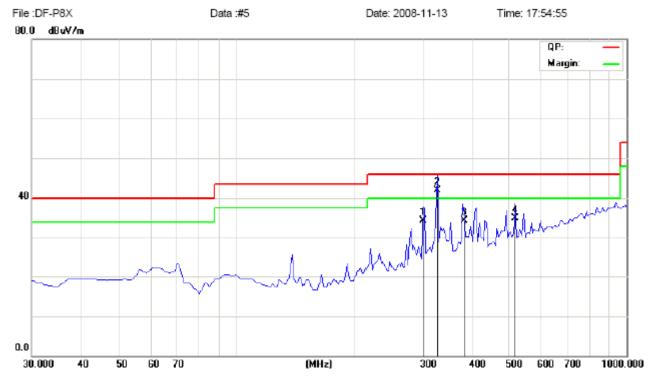


EUT set Condition: Reading SD Card

Level: Class B
Results: PASS

Please refer to following diagram for individual

Picture of the test



Frequency (MHz)	Level@3m ($dB\mu V/m$)	Antenna Polarity	Limit@3m ($dB\mu V/m$)
299.606	34.38	Н	46.00
327.249	41.89	Н	46.00
382.217	34.40	Н	46.00
517.885	34.97	Н	46.00

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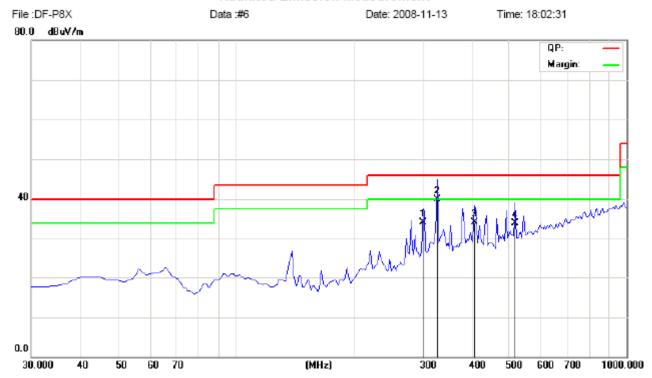
F: Radiated Disturbance In Vertical (30MHz --- 1000MHz)

EUT set Condition: Reading SD Card

Level: Class B
Results: PASS

Please refer to following diagram for individual

Picture of the test



Frequency (MHz)	Level@3m ($dB\mu V/m$)	Antenna Polarity	Limit@3m ($dB\mu V/m$)
300.106	34.10	V	46.00
327.369	39.88	V	46.00
408.886	34.19	V	46.00
517.622	33.87	V	46.00

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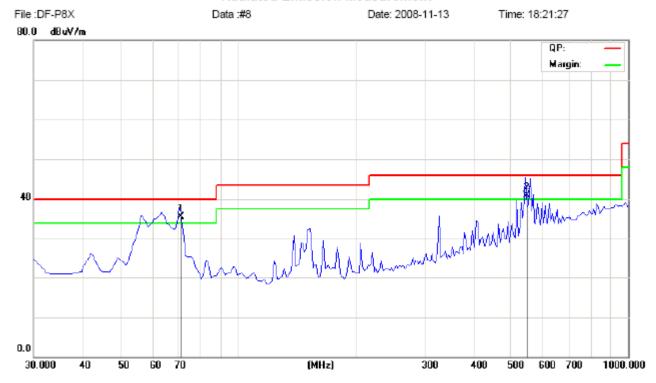
G: Radiated Disturbance In Horizontal (30MHz----1000MHz)

EUT set Condition: Reading USB

Level: Class B
Results: PASS

Please refer to following diagram for individual

Picture of the test



	Frequency (MHz)	Level@3m ($dB\mu V/m$)	Antenna Polarity	Limit@3m ($dB\mu V/m$)
	71.147	35.52	Н	40.00
I	547.964	40.82	Н	46.00

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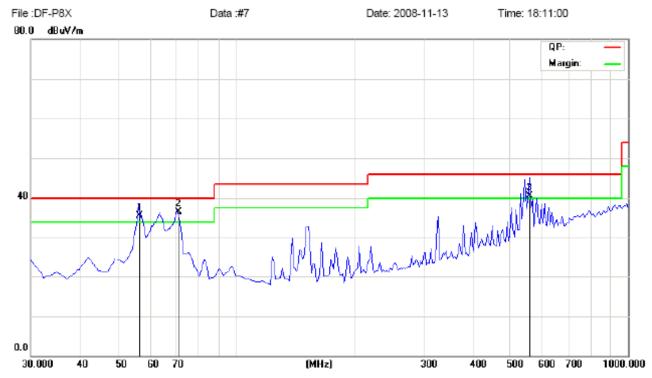
H: Radiated Disturbance In Vertical (30MHz---1000MHz)

EUT set Condition: Reading USB

Level: Class B
Results: PASS

Please refer to following diagram for individual

Picture of the test



Frequency (MHz)	Level@3m (dBµV/m)	Antenna Polarity	Limit@3m (dBµV/m)
56.518	35.50	V	40.00
71.191	36.42	V	40.00
558.961	40.45	V	46.00

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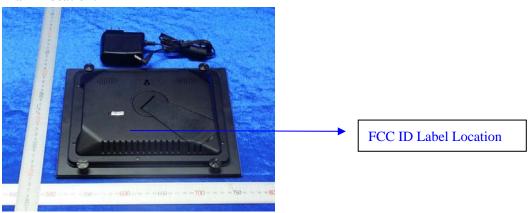
6.0 FCC ID Label

FCC ID: V37-SEMIDIA8INCH

This device complies with part 15 of the FCC rules. Operation is subject to the following two conditions (1) this device may not cause harmful interference, and (2) this device must accept any interference received, including interference that may cause undesired operation.

The label must not be a stick-on paper label. The label on these products must be permanently affixed to the product and readily visible at the time of purchase and must last the expected lifetime of the equipment not be readily detachable.

Mark Location:





7.0 Photo of testing

7.1 Conducted test View-





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7.2 Radiated emission test view--



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Photo for the EUT





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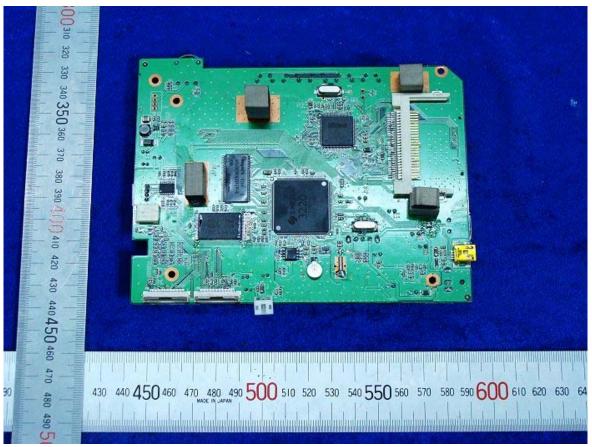
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-End of the report-